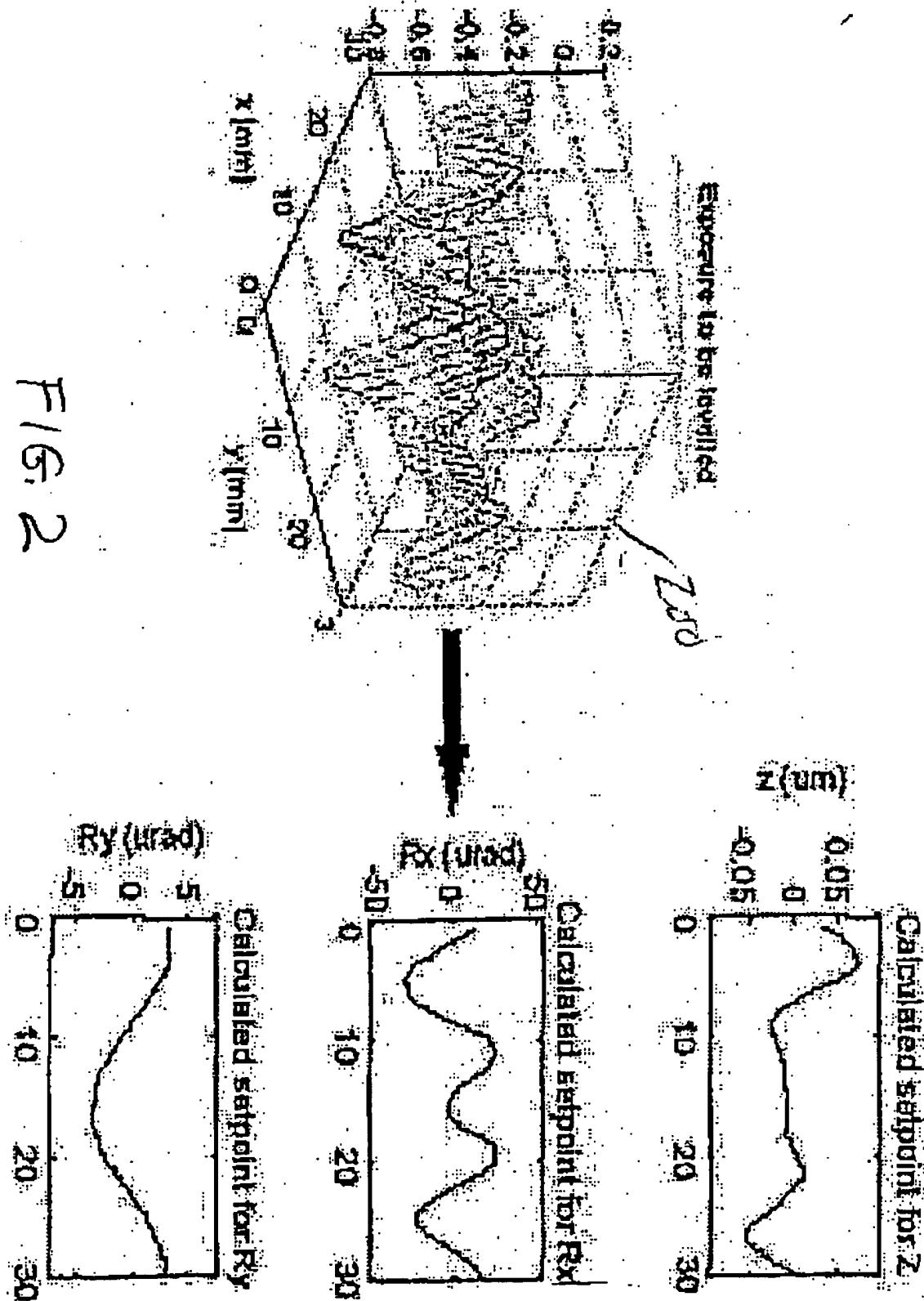


FIG. 1

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FOCUS SPOT STATISTICS

Wafer	Chuck ID	Deviations		
		X [mm]	Y [mm]	deviation [um]
1	1	-141.32400	-7.80000	0.542148
1	1	-126.69160	-66.64960	1.295974
1	1	-126.69160	51.04960	0.550704
1	1	-112.05920	-66.64960	1.506365
1	1	-68.16200	-96.07440	0.456564
1	1	-68.16200	109.89920	0.895035
1	1	-53.52960	-125.49920	1.113183
1	1	-53.52960	109.89920	0.443870
1	1	-9.63240	139.32400	0.786096
1	1	5.00000	-125.49920	1.681745
1	1	63.52960	109.89920	0.573930
1	1	78.16200	109.89920	1.017531
1	1	92.79440	-96.07440	0.922599
1	1	107.42680	80.47440	1.547343
1	1	122.05920	-66.64960	0.665561
1	1	136.69160	-37.22480	0.404567
1	1	136.69160	-7.80000	0.405736
1	1	136.69160	21.62480	0.503015
2	2	-141.32400	-7.80000	0.543358
2	2	-126.69160	-66.64960	1.231986
2	2	-126.69160	51.04960	0.542519
2	2	-112.05920	-66.64960	1.486671
2	2	-82.79440	109.89920	0.778743
2	2	-68.16200	-125.49920	0.523200
2	2	-68.16200	-96.07440	0.488616
2	2	-68.16200	109.89920	0.812353
2	2	-53.52960	-125.49920	1.139583

FIG. 3

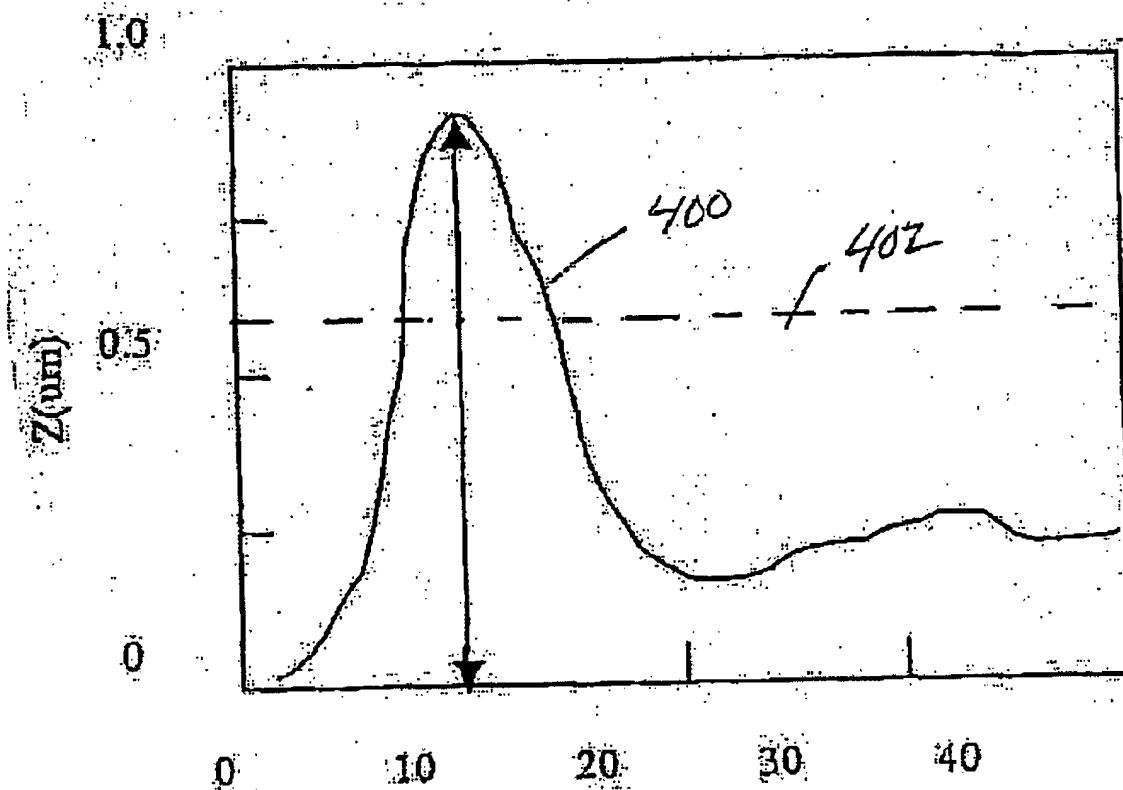


FIG. 4

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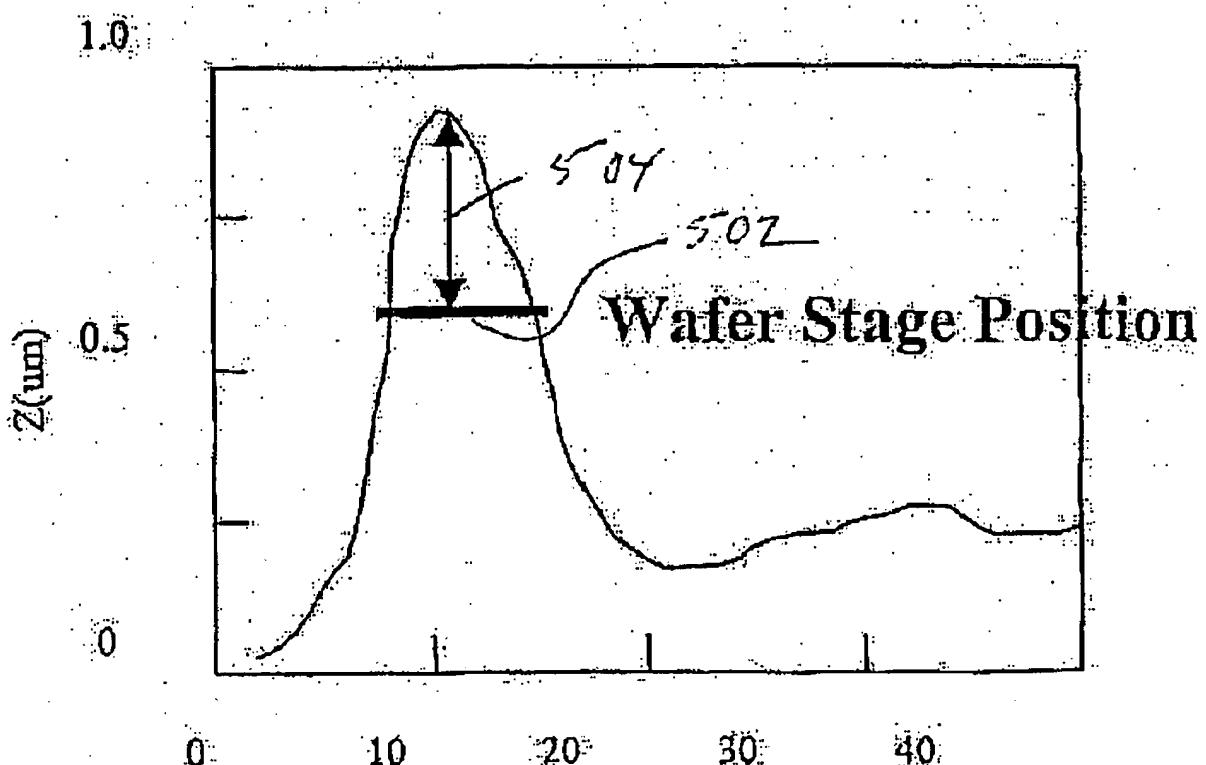


FIG. 5

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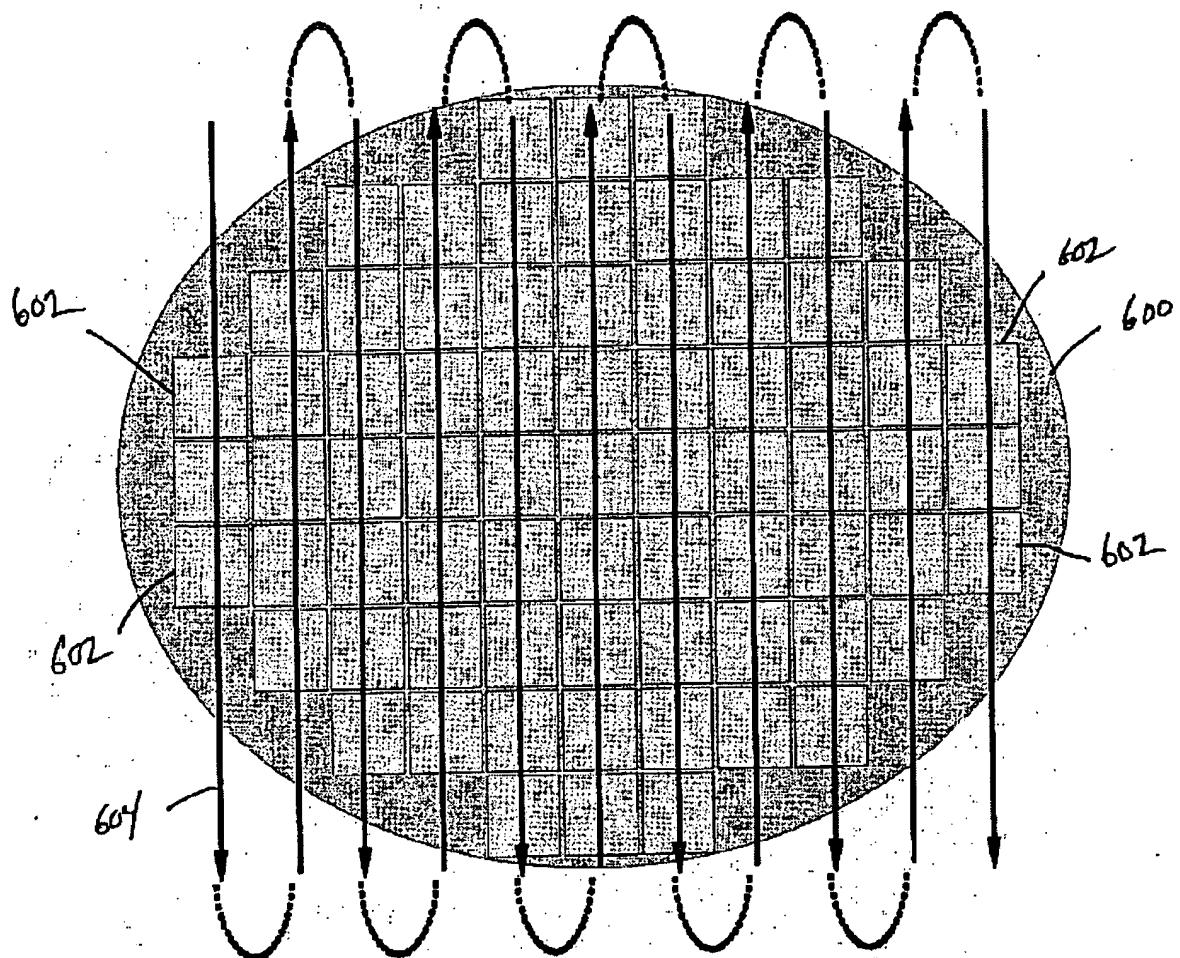


FIG. 6

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Exposure Area

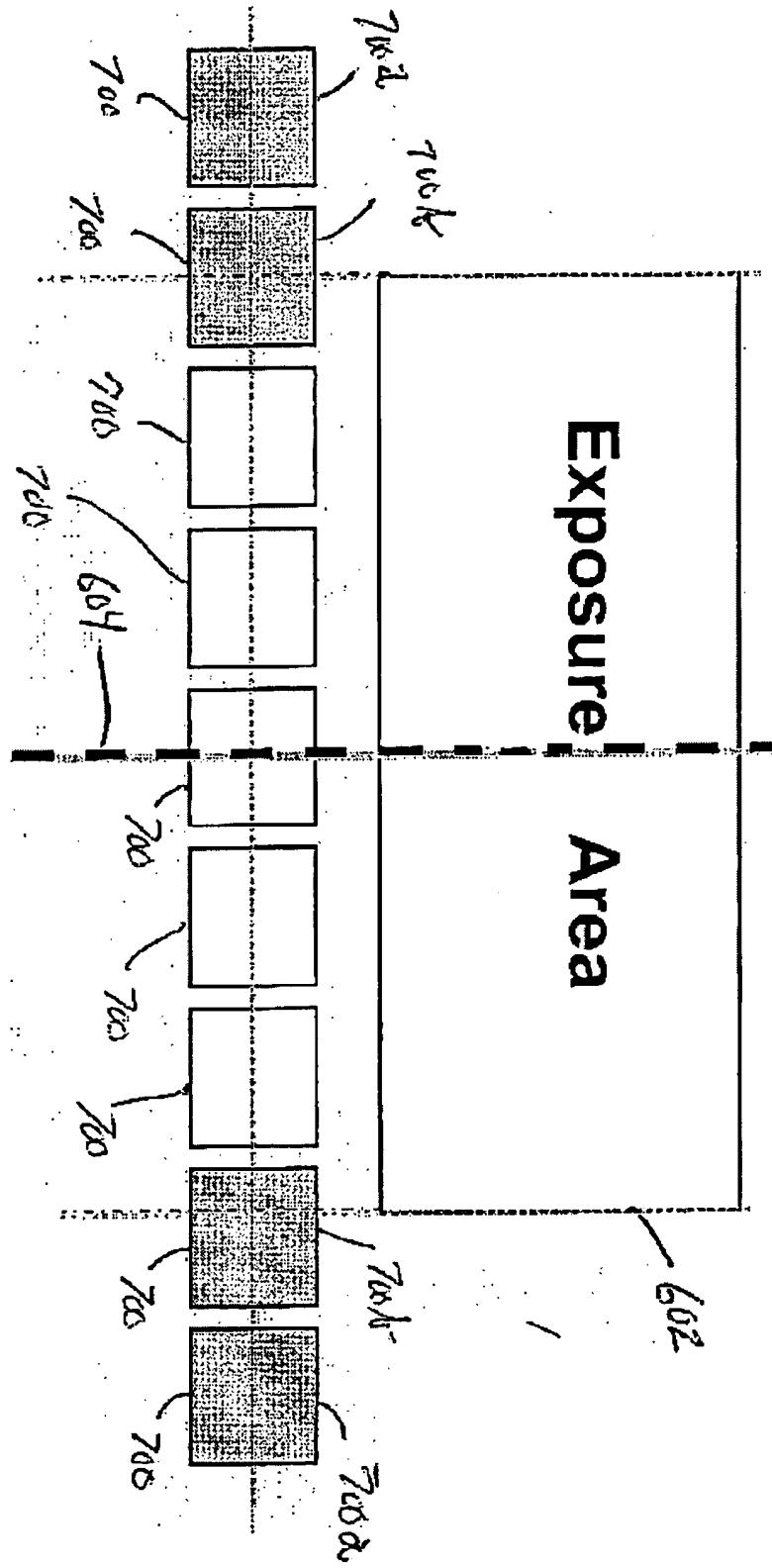


FIG. 7

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